

THE APPLICATION OF TECHNOLOGY ACCEPTANCE TO EDUCATIONAL DESIGN

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Dr. Gary L. Ackerman

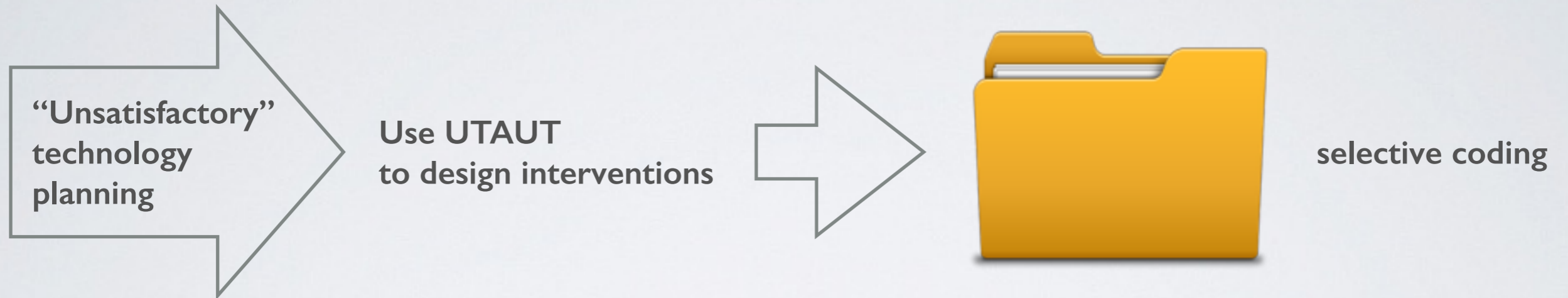
Rivendell Academy and Mount Wachusett Community College
gary.hackscience.net@gmail.com
@garyackermanphd

<http://www.hackscience.net>

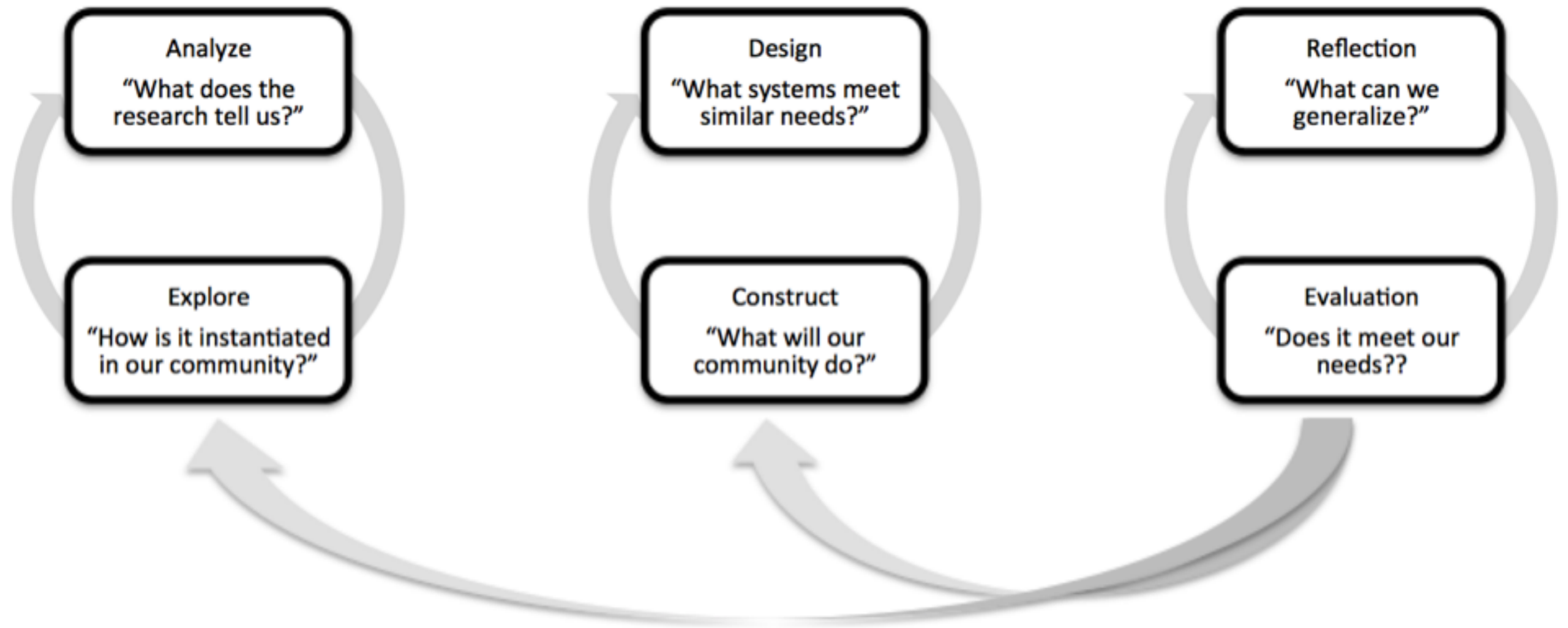
OVERVIEW

- The data
- Educational Design Research & UTAUT
- The designs
- Exploratory findings

THE DATA

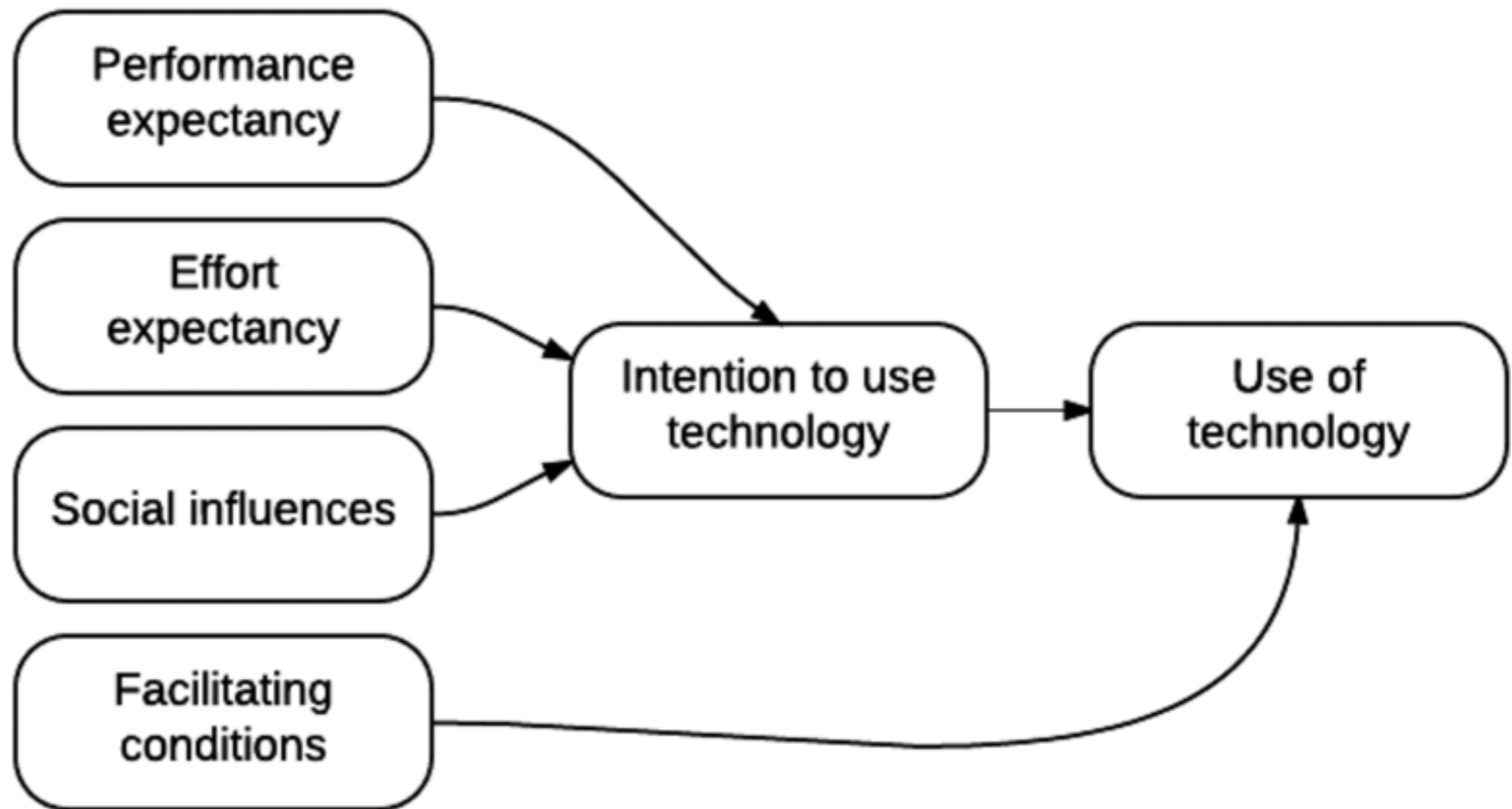


EDUCATIONAL DESIGN RESEARCH



Adapted from McKenny, S., & Reeves, T. (2012). *Conducting educational design research*. New York: Routledge.

UNITED THEORY OF ACCEPTANCE AND USE OF TECHNOLOGY



OUR APPROACH TO THE PROBLEMS

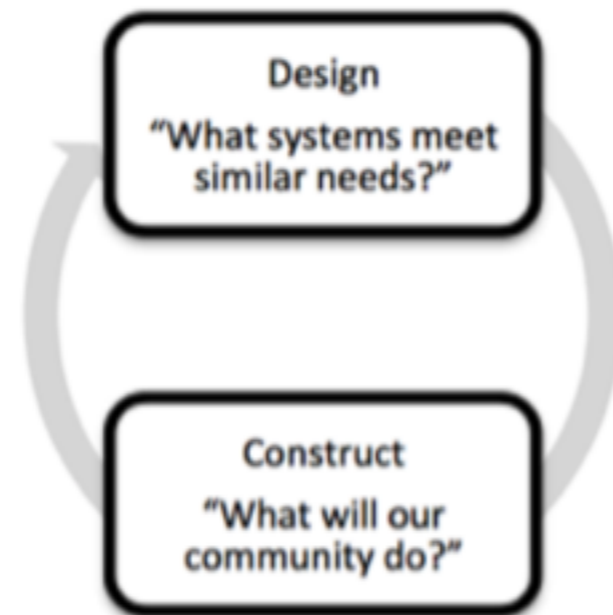


Problem is defined

Ackerman: "Here is UTAUT"

Refine problem & charge the group

OUR APPROACH TO THE DESIGNS



Design
Redesign
Days to years

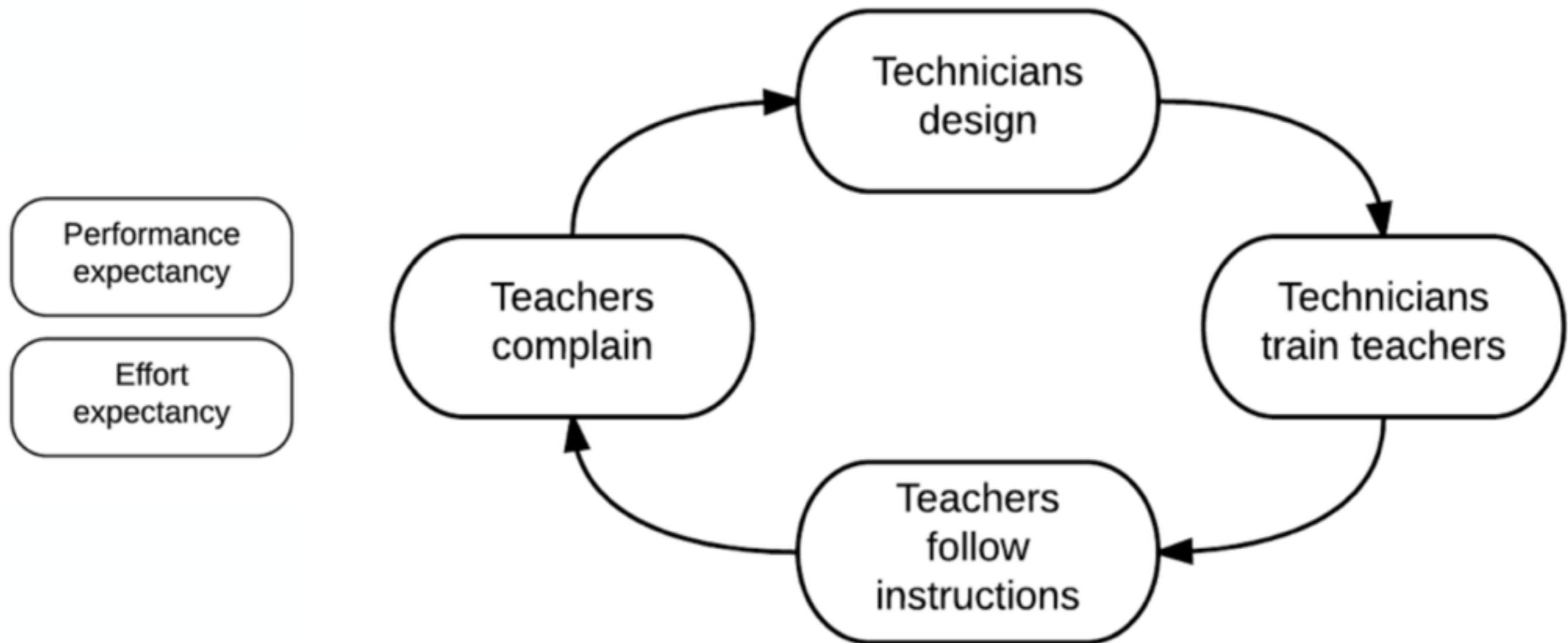
OUR APPROACH TO EVALUATION



Subjective determination of participants

Exploratory findings

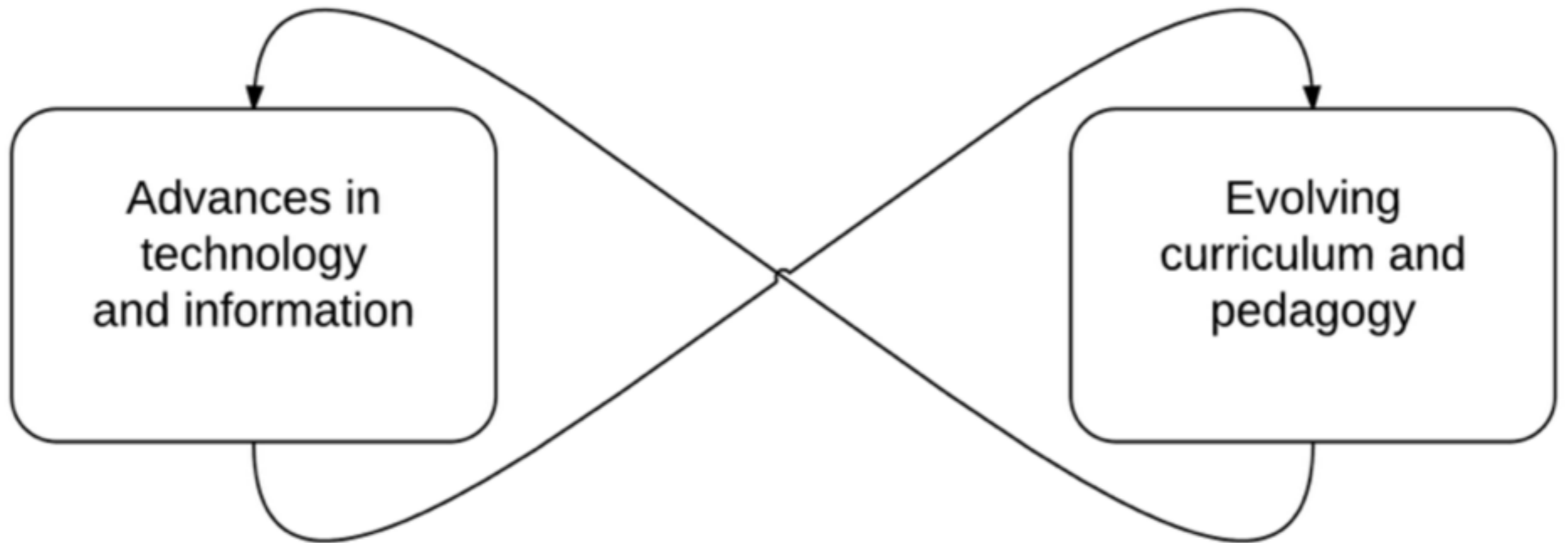
DESIGN # 1: PLANNING CYCLE



Gerry's formal implementation in a secondary school

Donna's less formal in primary grades

DESIGN #2: REFLEXIVE CURRICULUM DESIGN



“PE on steroids”

“Everyone had a reference section” “I can teach best-fit line”

DESIGN #3: CURRICULUM REPOSITORY



“LMS got easier to use” “More useful than OER” New hires

FRAMING INTERVENTIONS

- General heuristics for wicked problems
- “Focus; and we sure needed it”
- “Educators can contribute to tech decisions”

FOUR EMERGING PROBLEMS

- Context matters for technology acceptance
Teacher - student, teacher - technician, subject matter
- Need for conceptual artifacts
Effort & performance expectancies, teacher - technician, subject matter
- Usefulness is quantum and irreversible
“I can’t not do this”
- **Autonomy & leadership: Unrecognized factors?**
Awareness and agency to affect change
The social influence of principals

REFERENCES

McKenny, S., & Reeves, T. (2012). *Conducting educational design research*. New York: Routledge.

Venkatesh, V., Morris, M., Davis, G., & Davis, F. (2003). User acceptance of information technology: Toward a unified view. *MIS Quarterly*, 27(3), 425–478.